

ULA (Ultra Low Alpha) Dedicated Line for



Presented by

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ASE (US) INC. Oct, 30, 2009

Santa Clara, USA

Content



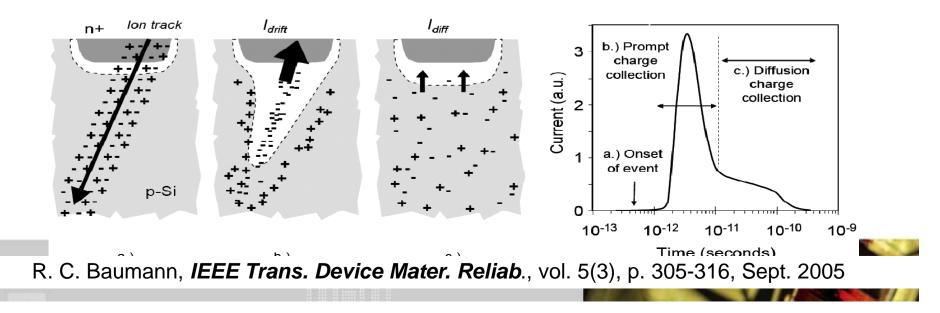
- Introduction
- Low Alpha Particle Control Strategy
- Raw Material Management
- Design / Layout Confirmation
- Dedicate Line for Assembly

Summary

Introduction - Soft Error



- Soft Error / SER (Soft Error Rate)
 - a. High energy particle creates electron-hole pairs in the silicon.
 - b. Charges drift and collect at nodes, producing a prompt current.
 - c. Charges diffuse toward the nodes, producing lower current.
 - d. When current accumulated large enough, memory states is switched.
 - e. <u>High chip density, smaller device dimensions & lower voltage</u> increase the susceptibility of memory devices to soft error. (SoC, SRAM, DRAM,...)



Introduction - Solution for Soft Error



- Three conditions to cause soft errors:
 - Present within 50 um of the device surface
 - With a direct line of travel to the device surface
 - Number of electrons storage well exceed critical charge Source: IEEE Transaction on Reliability, Soft Errors Induced by Alpha Particle (1996)
- To eliminate the alpha particles:
 - Less susceptible design (Move source away from devices).
 - Add shielding (Die coatings or polyimide thin film)
 - Packaging materials (Using low / ultra low alpha particle)

Source: Tezzaron Semiconductor, Soft Error in Electronic Memory - A White Paper (2004)





Low Alpha Particle

Control Strategy



Low Alpha Particle Control - Scope



Material been monitored:

- 1. Molding Compound/ Liquid Encapsulant
- 2. Solder Paste.
- 3. Flip Chip Underfill.
- 4. Epoxy/ Epoxy Film (for STK PKG)
- 5. Substrate Pre-solder.

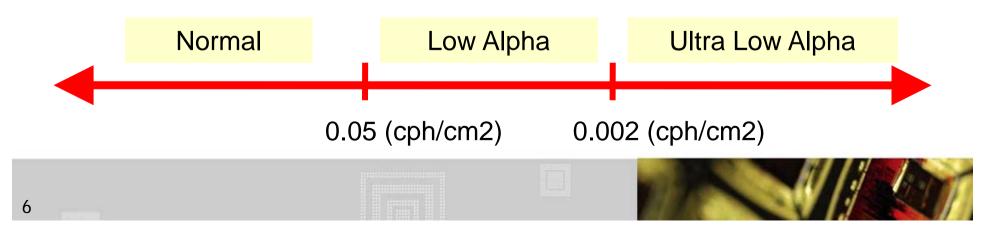
New Device:

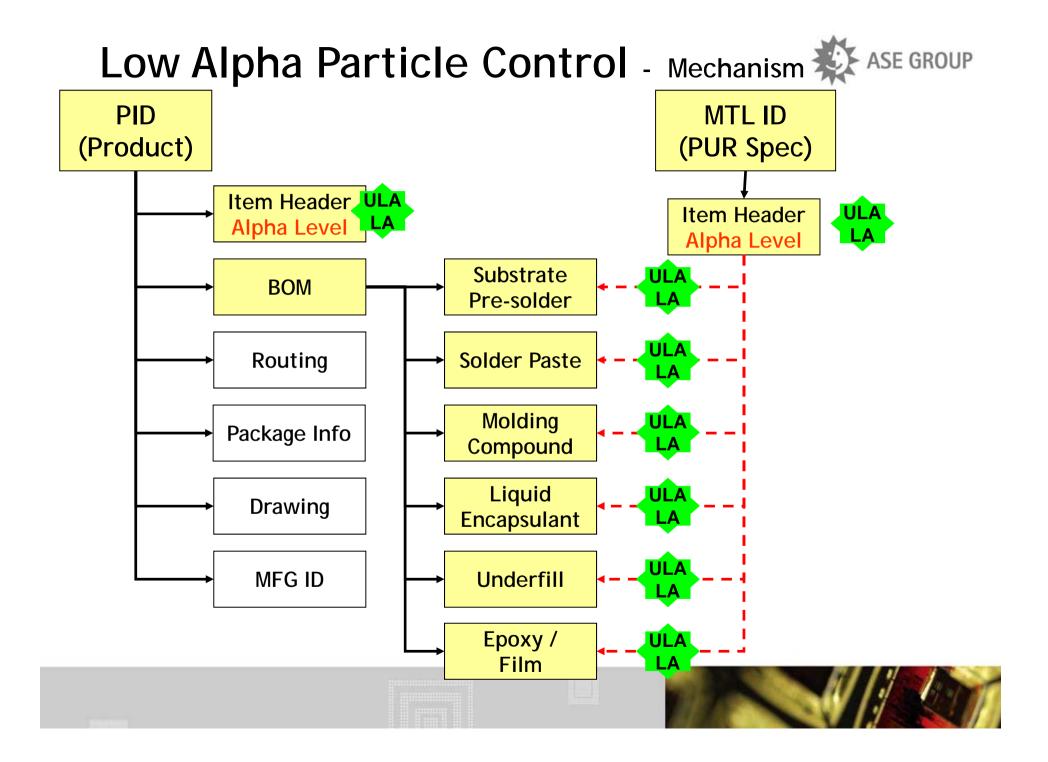
Define Control Level in PDM. after aligning with Customers.

Old Device:

No Action. unless have any Special instruction.

Material alpha particle control level criterion (unit : count/hour-cm²)





Low Alpha Particle Control - Working Plan 🗱 ASE GROUP

Work Item	Q1	Q2	Q3	Q4
A. Organization				
A.1 Teaming Up (CDE/CPE/MPE/QA/Pricing/PUR/MM/IQA/MFG/MIS)				
A.2 Role & Responsibility, KPI Definitions				
B. Basic Data Preparation				
B.1 Material PUR Spec Buildup for Alpha Ray control Level				
B.2 Vendor Inspection Report Collection & Buyoff				
C. IT System Development				
C.1 New Data Item & Checking Logic Coding				
C.2 Table Creation & Data Migration				
D. Engineering Preparation				
D.1 Training & Certification for ASE Alpha Control Policy				
D.2 APQP, AMQP, RA, Design Flow Modification				
E. Manufacture Preparation				
E.1 Management & Containment of Radioactive Contaminants				
E.2 Training & Certification for ASE Alpha Control Policy				
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Raw Material

Management

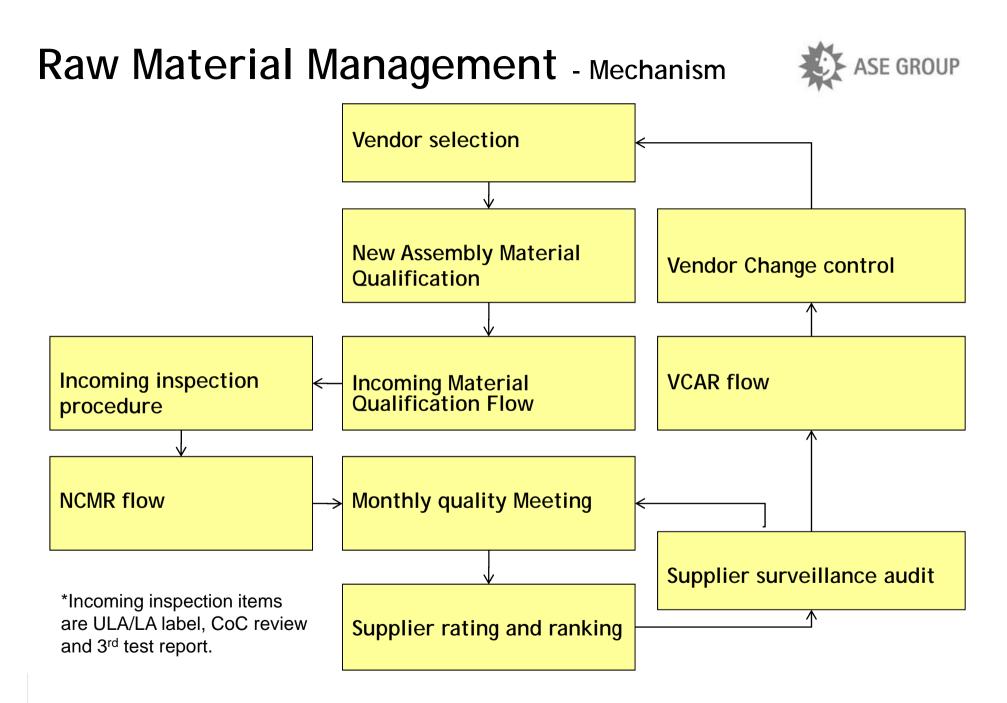


9

Raw Material Management - by package



- Wire Bond (L/F & BGA) Package
 - Molding Compound/ Liquid Encapsulant
 - Epoxy / Epoxy Film (for STK PKG)
- Flip Chip package
 - Solder Paste for chipcap
 - Underfill
 - Substrate (pre-solder) for FC bond.
 - Molding Compound (for MFC PKG)
 - Epoxy / Epoxy Film (for STK PKG)
- WLP package
 - Solder Paste for printing
 - *Anode / Plating solvent for plating



Raw Material Management - measurement capability GROUP

Measurement Capability set up :

In-house or certified third Party for ULA monitoring

Co-work with Third party to set up ULA measuring capability :

- * Equipment Survey:
- * Test Method Survey:
- * Certification Standardization :



Raw Material Management - PID release system ASE GROUP

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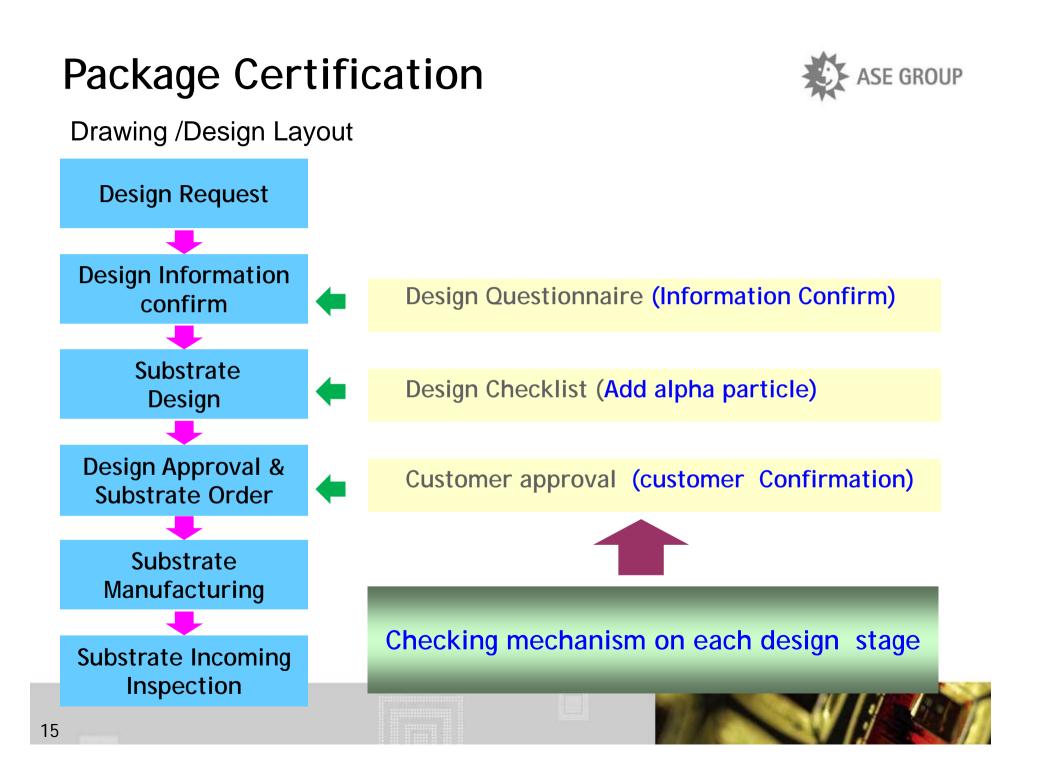




Drawing / Design Layout

Confirmation





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Drawing /Design Layout

17

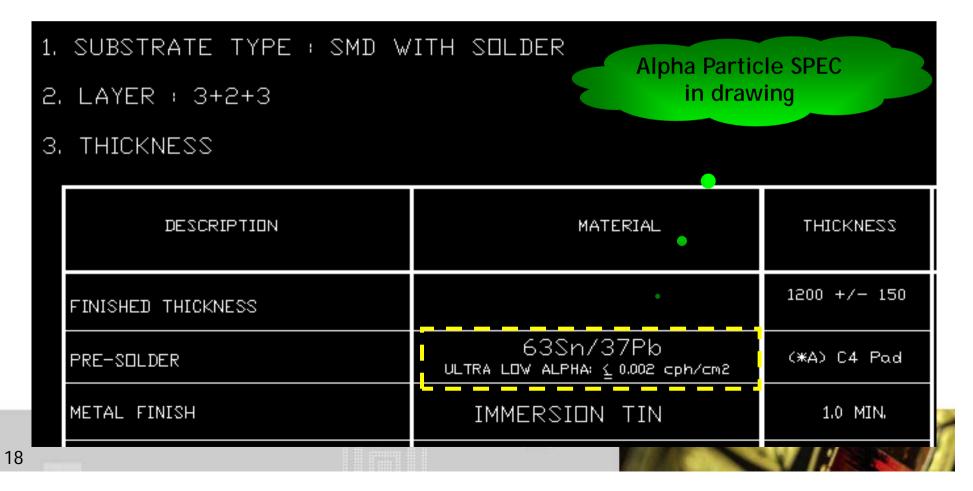


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Drawing /Design Layout

- ULA substrate has different layout drawing #.
- ULA substrate requirement is specified in layout drawing.





ULA Product Confirmation

RA (Risk Assessment): Product Engineer will check ULA information

- TO SEE if any Embedded memory designed inside chip/ package
- To Check what is the ULA Alpha particle level requirement



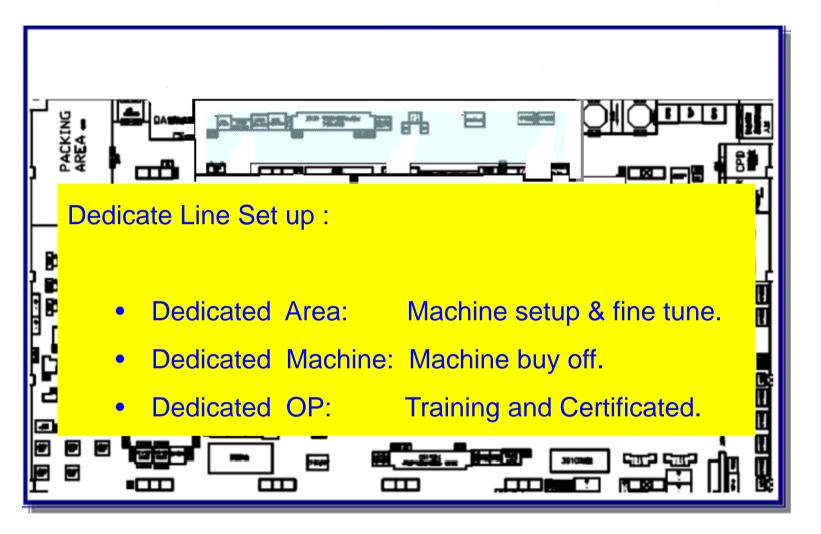


Dedicated Line for

FC BGA Assembly





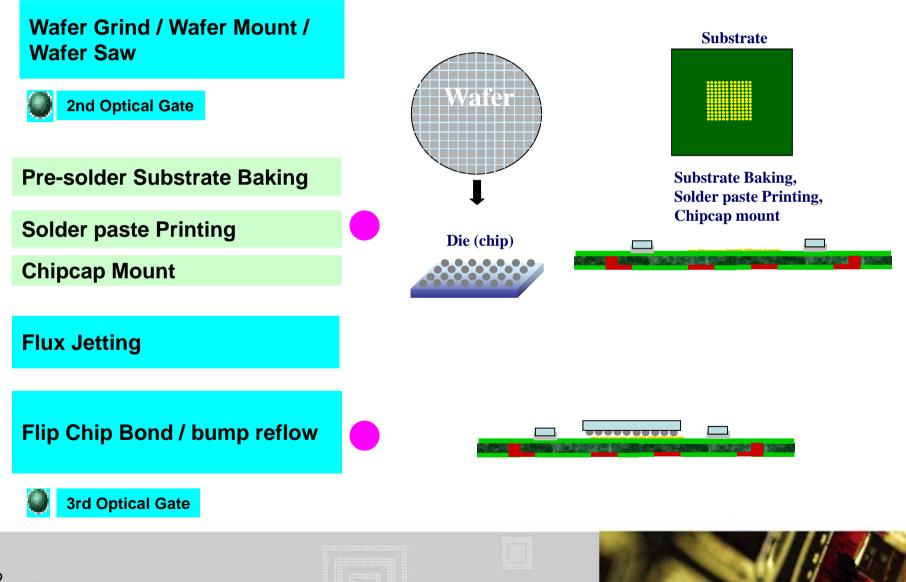




Dedicate Line Certification



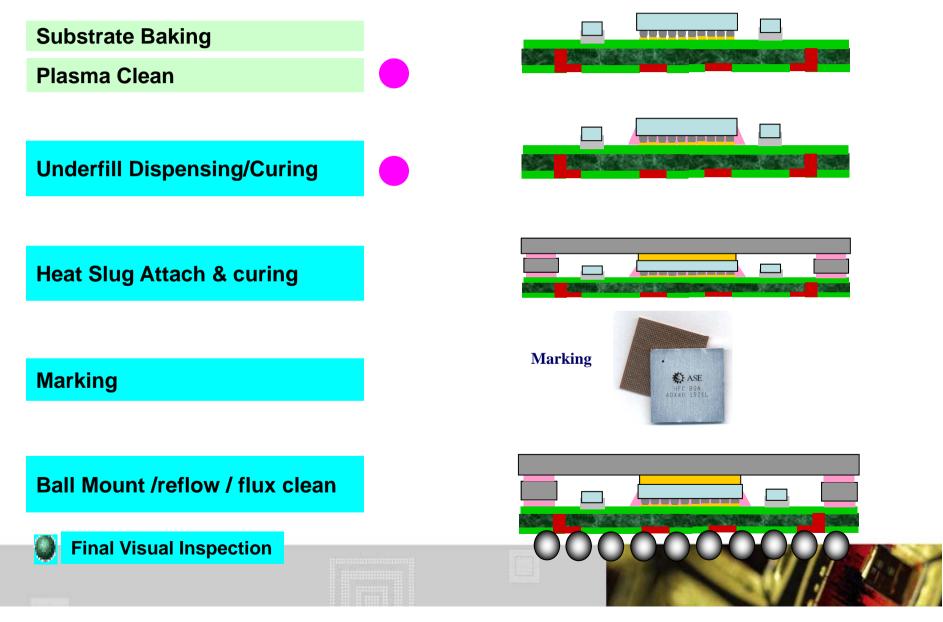
Dedicate Machine for ULA Control.



Dedicate Line Certification



Dedicate Machine for ULA Control.



Dedicate Line Certification



MES System:

- Only Certified ULA Operator to handle ULA products
- Only **ULA material** been used in ULA products
- Only **ULA machine** can process ULA products.



Bar code Control

Rules by Lot		ASE_AssignSubstateLotHo		
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Summary



1. A dedicated FC line with completed control mechanism :

ULA requirement identification,

Packaging design procedure control

Raw material control,

In line process control,

Production certification.

2. WB product has validated existing control mechanism : Prevent the alpha particle contamination.



Thank you

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